<u>Advanced OmniScan User Course</u>

<u>Introduction</u>

This course is only for personnel that have already successfully completed the TEST NDT, 40 hour   Phased Array course and have gained experience using the OmniScan for various applications.

This course will include a brief review of some of the more advanced topics covered in the standard 40 hour course and will expand the attendees knowledge into some of the more advanced capabilities of the OmniScan.

The course consists of a series of hands on demonstrations using the OmniScan through a projector, by the instructor which will then be followed by each student repeating the exercises using their own instruments under supervision and guidance of the instructor.

On successful completion of this course the attendee should feel confident to perform the following functions:

1. Updating software versions using web supplied downloaded software

2. Defining "non standard" probes

3. Importing and exporting probe definitions

4. Defining non standard wedges

5. Importing and exporting wedge definitions

6. Review of Ultrasonic Phased Array procedure development/programming

7. Review of Process control checks and calibrations, including: Encoder, DAC, TCG, Sensitivity, wedge delay

8. Using cursors for accurate sizing from encoded "C scan" images

9. Setting up reading fields

10. Building a defect table and importing into reports

11. Creating and saving data files

12. Importing data files into Tomoviewer

13. Using "Tomoviewer" to analyze data files

14. Setting up and using the "Multi-group" option for simultaneous scanning

15. Creating new color palettes

16. Setting up palettes and gain for 6 dB drop plotting C scan

17. Linking html procedures to set up files

18. Creating custom reports

19. Changing company logo in reports

20. Setting up USER menu

21. Locking/Unlocking a set up to only allow the user group adjustments

22. File manager tasks

23. Linking OmniScan to PC for data transfer

24. Advanced gate functions

25. peak or flank

26. different measurement points

27. Interface lock feature

28. explanation of flashing gates

29. Using the "A scan" envelope feature

30. Fast Furrier Transfer feature

31. Tomoview overview and practical exercises

A detailed course manual covering the above functions in a step by step format will be provided to each attendee.

Attendees are encouraged to bring along their own instruments and probes or at least their own Compact flash cards, so that work performed during the course can be kept by the attendee.

Any actual defect samples that the attendees are using phased array techniques on may also be brought to the course for procedure development help during the course.

(A certificate of course attendance will be given to each attendee and the course can be used for ASNT NDT Level III re-certification points).

For further details or to discuss your individual requirements, please call Richard Harrison

(USA) 714 255 1500 or (UK) 1772 616913